



PEST MANAGEMENT & CROP DEVELOPMENT

BULLETIN

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Extension Entomologist

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Last Issue in 2003

Wow, what a year! From my perspective, 2003 will be one of the most memorable years in my career. Insects kept us hopping throughout the summer, not the least of which were soybean aphids, Japanese beetles, and the ever-present western corn rootworm. We have so much to talk about during winter meetings that our primary difficulty will be prioritizing which insects and insect management strategies to discuss. Through meetings with other entomologists during the next 3 to 4 months, I anticipate learning some insect-management pointers that will be valuable to agriculturists throughout Illinois. I look forward to sharing more with you in the months to come.

I and the other contributors can't thank you enough for all of the information you provided last year. The two-way communication that derives from such reporting is very rewarding and useful for the many readers of the *Bulletin*. As a result of significant exchanges of information and ideas, we are able to keep a lot of people abreast of the pest situation, crop development, and agricultural issues. So you should always realize how much importance we place on the dialogue we maintain throughout the year.

As I indicated last year, education and information have always been the dual objectives of the *Pest Management & Crop Development Bulletin*. Consequently, we, the authors, use the *Bulletin* as one of our primary media to share what we learn. With reports from the field, we try to keep you abreast of pest developments throughout Illinois and elsewhere in the Midwest. With results from our applied research efforts, we try to keep you abreast of the latest developments in pest management technology and techniques. We hope you rely on our articles to help you prepare for and manage pest problems in ways that are both economic and environmentally sound.

On behalf of all of the authors and other contributors to the *Bulletin*, I thank you for your continued interest in our efforts and for the support you have provided for so many years. We look forward to working with you again in 2004. During the forthcoming holidays, take ample time to relax, and enjoy the time you spend with family and friends. And take some extra time to reflect on the wondrous opportunities, challenges, and bounties we have in this country. We are blessed in so many ways. Please have a happy and safe holiday season.—Kevin Steffey

2004 Illinois Crop Protection Technology Conference

The 2004 Illinois Crop Protection Technology Conference will be held at the Illini Union on the University of Illinois campus January 7 and 8. The conference will feature a wide variety of topics, with presentations by experts from the University of Illinois, the University of Wisconsin, Cornell University, Michigan State University, Ohio State University, Kansas State University, Southern Illinois University, the Illinois Department of Agriculture, and the Environmental Protection Agency. In addition, several speakers from the private sector will play an important role in the conference. A detailed summary of the program follows.

Keynote session—Trends and Future (1.0 CCA credit in Crop Management and 1.0 CCA credit in Pest Management)

- Trends and Future: Agriculture
- Trends and Future: Integrated Pest Management
- Trends and Future: Seed Industry
- Trends and Future: Agrichemical Industry

Six symposia (three or four presentations within each symposium)

- Pest Resistance (1.5, Pest Management)
- Equipment and Application Technology (0.5, Soil and Water Management; 1.0, Pest Management)
- Seed Purity Issues (1.5, Crop Management)
- Emerging and Challenging Pest and Production Issues (1.0, Pest Management; 0.5, Crop Management)
- Pesticide Repackaging, Storage, Transport, and Application Concerns (1.5, Soil and Water Management)
- New Developments in Crop Protection Products (1.5, Pest Management)

Fifteen seminars (single presentations with smaller group interactions)

- Herbicide Persistence in the Soil Environment (1.5, Soil and Water Management)
- Corn Diseases and Their Management (1.5, Pest Management)
- Retail Seed Treatment 101 (1.5, Pest Management)
- Management of Forages for Better Yield and Profit (1.5, Crop Management)
- Identification and Management of Winter Annual Weed Species (1.5, Pest Management)
- Crucial Conversations, Tools for Talking When Stakes Are High (1.5, Professional Development)
- Got Dead Stuff (1.5, Pest Management)
- Cleaning Up Your Act—Reducing Pesticide Cross-Contamination (1.5, Soil and Water Management)
- Water Quality Research in Illinois (1.5, Soil and Water Management)
- PDA Use and Data Management (1.5, Professional Development)
- Corn and Soybean Nematodes (1.5, Pest Management)

- Field Crop Scouting Calendar and Techniques (0.75, Pest Management; 0.75, Crop Management)
- The White Grub Complex in Corn (1.5, Pest Management)
- Pandora's Pond (1.5, Soil and Water Management)
- Corn Rootworm Management in the Corn/Soybean Cropping System (1.5, Pest Management)

The preregistration form in this issue indicates the four ways you can register for the conference. We wish you a happy and safe holiday season, and look forward to welcoming you to the 2004 Illinois Crop Protection Technology Conference.—*Aaron Hager*

Corn and Soybean Classic Meetings in January

For the seventh consecutive year, University of Illinois Extension specialists will offer Corn and Soybean Classic meetings at several sites in January. The response to these meetings has been very positive, and we always look forward to the interactions there. If you have attended one or more meetings in the past, we hope to see you again in 2004. If you have never attended, make a point to attend in 2004.

We believe we have another informative program for 2004, with speakers who will address critical issues in crop production and crop protection. After a series of relatively brief presentations (usually 25 minutes each) in both the morning and afternoon, we hold panel discussions with the audience for about 30 minutes. The interaction usually is one of the highlights of the meetings.

Following are dates, locations, certified crop advisor credit (CCA) information, and a list of the presentations that will be given at each meeting.

Dates and Locations

- 1/13—Bloomington (Interstate Center)

- 1/14—Rochelle (Hickory Grove Banquet Center)
- 1/15—Moline (Mark of the Quad Cities)
- 1/20—Mt. Vernon (Holiday Inn)
- 1/21—Collinsville (Holiday Inn)
- 1/22—Springfield (Crowne Plaza)

Topics and Speakers

- Chasing High Corn and Soybean Yields—Emerson Nafziger
- Do You Need Micronutrient Soil Tests?—Bob Hoelt
- Developments in Agricultural Drainage in Illinois—Richard Cook
- Interactions Between Weather and Crop Disease—Dean Malvick
- The Soybean Checkoff Wants to Give Back \$\$\$ That SCN Is Taking Away—Terry Niblack
- Methods, Performance, and Price Impacts of USDA Crop Forecasts—Darrell Good
- The Changing Picture in Insect Management: New Tactics, New Invasive Pests, and Unknown Relationships—Kevin Steffey or Mike Gray
- The Wise, the Unwise, and the Otherwise: The Spectrum of Weed Management Practices—Aaron Hager

Certified Crop Advisor Credits

- Nutrient Management—1.0
- Crop Management—1.0
- Integrated Pest Management—3.0
- Soil and Water Management—1.0

A preregistration form in this issue details your advance registration options and costs. You can register on site (\$50) by bringing the form and your payment on the date of your chosen conference. On-site registration will begin at 8:15 a.m., and each conference will adjourn at 3:15 p.m. Travel schedules may require changes in the order of speakers.

If you have questions about registration or scheduling, please contact Conferences and Institutes at (217)333-2880. If you have questions about the program content, contact Bob Hoeft at (217)333-4424. We hope to see you at one of the Classics.—*Kevin Steffey*

Soybean Aphid and Pest Resistance Programs Early Next Year

Two pest management programs that should be of great interest to many people in Illinois will be presented via Latitude Bridge in February and March 2004. "Soybean Aphids—What We Learned in 2003, and How We'll Manage These Pests in the Future" will be presented by entomologists from four states on February 5. Marlin Rice (Iowa State University), Ken Ostlie (University of Minnesota), Eileen Cullen (University of Wisconsin), and entomologists from the University of Illinois (David Voegtlin and Kevin Steffey) will deliver the program from their respective campuses to audiences throughout the four-state region. Information discussed during the program, which begins with registration at 8:30 a.m., will include soybean aphid biology and occurrence in North America; the soybean aphid situation in Illinois, Iowa, Minnesota, and Wisconsin; research efforts in the four states; and thresholds and guidelines for making treatment decisions. The program will conclude at 3:00 p.m. CCA continuing education units have been applied for. For more information about the program, contact your local Extension office. Extension personnel in each state will make the arrangements to host the program in their respective areas.

Two pest resistance programs will be presented on March 5 and March 12. Kevin Steffey and Aaron Hager will discuss issues associated with insect resistance and weed resistance, respectively, on March 5. Dean Malvick and Terry Niblack will discuss issues associated with plant pathogen resistance and nematode resistance, respectively, on March 12. For more information, contact your local Extension office.

The Latitude Bridge enables presenters to deliver a program from a central location over the Internet to audiences at numerous locations. The programs will be hosted by county or regional extension offices that can project PowerPoint slides and receive audio input. The presenters control the slides and offer commentary as the slides are shown. Listeners will be able to interact with the presenters, asking questions and offering observations.

We will provide specifics about these programs in a future issue of the *Bulletin*. Announcements also will be released by extension offices that will host the programs, so keep your eye on the local press. We hope you can participate in one or both of the programs.—*Kevin Steffey*

Scouting Preparation for 2004 Season

The much anticipated fifth edition of our popular *Field Crop Scouting Manual X880d* is nearly here! University of Illinois Extension specialists and educators and our ITCS publishing staff have been hard at work this past season revising the manual. You can expect the new edition to be ready for purchase early in 2004. The new edition has 30% more full-color photographs than the previous edition and contains more than 230 pages. Each chapter has been revised and updated to give you the most current information on scouting for significant pests in Illinois and the Midwest.

For more information about the new *Field Crop Scouting Manual X880d*, contact ITCS at (800)345-6087 or online at www.aces.uiuc.edu/ITCS/IM, after January 15.—*Suzanne Bissonnette*

INSECTS

Yield Information from 2003 Rootworm-Control Trials

In issue no. 22 (September 5, 2003) of the *Bulletin*, we provided root ratings from the three rootworm control trials

we conducted in 2003. In this issue, we provide the root ratings again, as well as yields from all three locations (Urbana—Table 1; Monmouth—Table 2; DeKalb—Table 3). However, you might notice a slight difference in the statistical significance of the root ratings in these tables. The averages have not changed, but the letters indicating differences among means according to Duncan's New Multiple Range Test are different from those presented in Table 4 in issue no. 22 of the *Bulletin*. As we explained in the accompanying article, two untreated check plots were included at all three sites—a DeKalb (DK) hybrid and a Northrup King (NK) hybrid. The DeKalb hybrid was the nontransgenic isolate of the DeKalb YieldGard Rootworm hybrid. The Northrup King hybrid was the hybrid planted in all other plots at all three sites. Consequently, Ron Estes, manager of the Insect Management and Insecticide Efficacy program in the Department of Crop Sciences, re-analyzed the data with the DeKalb hybrids not included. However, we provide both the average root ratings and yields for the two DeKalb hybrids, without letters associated with Duncan's New Multiple Range Test.

I'm not certain how much the yield data tell us. The root ratings were relatively easy to explain, as we wrote in the article in issue no. 22 of the *Bulletin*. However, as you can determine for yourself, the yield data do not necessarily correlate well with the root-rating data. This is particularly true for the data from the Urbana site. We had excellent growing conditions at that site in 2003, and the Northrup King hybrid in the untreated check compensated for the root damage quite well. At the Monmouth site, where the growing conditions were not quite as good as they were at the Urbana site, the untreated check plots took serious hits in yield, demonstrating the potential for rootworm larvae to cause significant yield losses. As you may recall, the trial at the DeKalb site was planted in late May. At all three sites, the YieldGard Rootworm hybrid had significantly higher yields than its nontransgenic isolines.

Table 1. Average root ratings and yields from the corn rootworm control trial in Urbana, Illinois, 2003.

Product	Appli- cation rate ¹	Place- ment	Avg root rating ^{1,2}	Avg yield (bu/ acre) ^{3,4}
Aztec 2.1G	6.7 oz	Band	2.10 d-g	163.7 a
Aztec 4.67G ⁵	3.0 oz	Band	2.15 c-g	141.5 a
Aztec 4.67G ⁵	3.0 oz	Furrow	2.30 c-g	165.1 a
Capture 2EC ⁶	0.35 oz	Band	2.55 b-f	144.3 a
Counter CR	6 oz	Band	1.90 g	132.7 a
Cruiser FS (seed treat- ment)	—	—	2.70 bcd	154.7 a
Empower	8.0 oz	Band	2.75 bc	166.5 a
Empower	8.0 oz	Furrow	2.60 b-e	139.1 a
Force 3G	4.0 oz	Band	2.20 c-g	142.7 a
Fortress 2.5G	7.4 oz	Furrow	2.00 efg	136.2 a
Fortress 5G ⁵	3.7 oz	Furrow	2.55 b-f	130.7 a
Fortress 5G ⁵	4.5 oz	Furrow	1.95 fg	140.8 a
Lorsban 15G	8.0 oz	Band	2.10 d-g	144.9 a
Poncho 1250 (seed treat- ment)	—	—	2.90 b	127.7 a
MON 863 (DeKalb Yield- Gard Root- worm hybrid)	—	—	1.35	142.2
Untreated check (De- Kalb hybrid)	—	—	5.45	105.2
Untreated check (NK hybrid)	—	—	4.60 a	157.8 a

¹ Rates of application are oz per 1,000 ft of row.

² Root ratings are from the 1-to-6 root-rating scale developed by Hills and Peters (1971).

³ Means followed by the same letter do not differ significantly according to Duncan's New Multiple Range Test, $P = 0.05$.

⁴ Plots (four 30-inch rows x 50 feet) were machine harvested.

⁵ Aztec 4.67G and Fortress 5G were applied through the SmartBox closed handling system.

⁶ Capture 2EC was applied at a volume of 5 gallons per acre.

These root-rating and yield data demonstrate very well the interaction of rootworm damage, corn hybrids, and environmental conditions. As we learned in a study we conducted in the early 1990s, under certain growing conditions, root damage that might otherwise be considered economic (a root rating >3.0) does not have a dramatic effect on yield. On the other hand, when growing conditions are poor, root damage that might otherwise be considered noneconomic (a root rating <3.0) can result in yield loss. Consequently, neither root ratings nor yield should be considered in isolation.—
Kevin Steffey and Mike Gray

2003 European Corn Borer Fall Survey: Densities Very Low in Most Areas of Illinois

With the generous cooperation of the crop systems and IPM Extension educators, the impact of European corn borers was

Table 2. Average root ratings and yields from the corn rootworm control trial in Monmouth, Illinois, 2003.

Product	Appli- cation rate ¹	Place- ment	Avg root rating ^{1,2}	Avg yield (bu/ acre) ^{3,4}
Aztec 2.1G	6.7 oz	Band	2.70 ef	108.6 ab
Aztec 4.67G ⁵	3.0 oz	Band	2.75 ef	103.7 ab
Aztec 4.67G ⁵	3.0 oz	Furrow	2.45 f	119.7 a
Capture 2EC ⁶	0.35 oz	Band	3.20 de	113.7 ab
Counter CR	6 oz	Band	2.20 f	126.8 a
Cruiser FS (seed treat- ment)	—	—	4.20 b	112.4 ab
Empower	8.0 oz	Band	4.15 b	105.1 ab
Empower	8.0 oz	Furrow	4.01 bc	109.8 ab
Force 3G	4.0 oz	Band	2.70 ef	110.7 ab
Fortress 2.5G	7.4 oz	Furrow	2.40 f	122.2 a
Fortress 5G ⁵	3.7 oz	Furrow	2.45 f	111.1 ab
Lorsban 15G	8.0 oz	Band	2.56 ef	128.6 a
Poncho 1250 (seed treat- ment)	—	—	3.45 cd	114.7 ab
MON 863 (DeKalb Yield- Gard Root- worm hybrid)	—	—	2.05	168.9
Untreated check (De- Kalb hybrid)	—	—	5.75	68.9
Untreated check (NK hybrid)	—	—	4.95 a	89.6 b

¹ Rates of application are oz per 1,000 ft of row.

² Root ratings are from the 1-to-6 root-rating scale developed by Hills and Peters (1971).

³ Means followed by the same letter do not differ significantly according to Duncan's New Multiple Range Test, $P = 0.05$.

⁴ Plots (four 30-inch rows x 50 feet) were machine harvested.

⁵ Aztec 4.67G and Fortress 5G were applied through the SmartBox closed handling system.

⁶ Capture 2EC was applied at a volume of 5 gallons per acre.

assessed in 51 Illinois counties (approximately 500 cornfields) this past fall. Results of the 2002 and 2003 fall European corn borer surveys are presented in Table 4. The results from the most recently completed survey continue to reveal a long-term pattern of very low overwintering densities of this insect pest. In 2003, the average percentage of plants (statewide) infested by European corn borers was 32.5%, and the average number of corn borers was 0.52 per plant. These numbers represent a very low infestation of corn borers that Illinois producers had to contend with during the 2003 growing season. In addition, these numbers suggest that a very small moth flight will occur next spring. Ultimately, the level of diseases (*Nosema pyrausta* and *Beauveria bassiana*) in overwintering larvae and environmental conditions during the first flight of moths next spring will be the key factor in regulating European corn borer populations in 2004. As producers make their seed-selection choices

Table 3. Average root ratings and yields from the corn rootworm control trial in DeKalb, Illinois, 2003.

Product	Appli- cation rate ¹	Place- ment	Avg root rating ^{1,2}	Avg yield (bu/ acre) ^{3,4}
Aztec 2.1G	6.7 oz	Band	2.15 c	113.7 bc
Aztec 4.67G ⁵	3.0 oz	Band	2.10 c	116.9 abc
Capture 2EC ⁶	0.35 oz	Band	2.70 bc	133.3 a
Counter CR	6 oz	Band	2.45 c	115.3 bc
Cruiser FS (seed treat- ment)	—	—	3.50 ab	118.4 abc
Force 3G	4.0 oz	Band	2.20 c	118.6 abc
Fortress 2.5G	7.4 oz	Furrow	2.20 c	124.9 abc
Fortress 5G ⁵	3.7 oz	Furrow	2.50 c	128.6 ab
Fortress 5G ⁵	4.5 oz	Furrow	2.55 c	121.8 abc
Lorsban 15G	8.0 oz	Band	2.65 c	121.6 abc
Poncho 1250 (seed treat- ment)	—	—	3.50 ab	120.0 abc
MON 863 (DeKalb Yield- Gard Root- worm hybrid)	—	—	1.45	149.3
Untreated check (De- Kalb hybrid)	—	—	4.06	112.9
Untreated check (NK hybrid)	—	—	4.20 a	111.6 c

¹ Rates of application are oz per 1,000 ft of row.

² Root ratings are from the 1-to-6 root-rating scale developed by Hills and Peters (1971).

³ Means followed by the same letter do not differ significantly according to Duncan's New Multiple Range Test, *P* = 0.05.

⁴ Plots (four 30-inch rows x 50 feet) were machine harvested.

⁵ Aztec 4.67G and Fortress 5G were applied through the SmartBox closed handling system.

⁶ Capture 2EC was applied at a volume of 5 gallons per acre.

this winter, we hope our survey data on overwintering densities of borers can be of some value in decision making.

From time to time, we're asked questions about how the survey is performed. Because it always has been conducted using the same sampling procedures, we can compare one year with the next. European corn borers are surveyed by selecting a cross-section of 10 fields throughout a county. Within each field, 25 consecutive plants are checked for any signs of corn borer injury (frass, exit holes, broken stalks). Surveyors make sure that the 25 plants are not within border rows and try to check plants 25 to 30 paces away from these field margins. After the number of plants infested is determined, two infested stalks are split and the borers are counted. County and statewide averages are then calculated for percentages of plants infested and numbers of borers per plant.

If you have any questions about the results of this survey, please give us a call or send us an e-mail message.—*Mike Gray and Kevin Steffey*

Table 4. Results of the 2002 and 2003 European corn borer fall surveys.

Counties	% plants infested, 2002	% plants infested, 2003	Borers per plant, 2002	Borers per plant, 2003
Adams	64.0	29.6	1.19	0.28
Alexander/ Pulaski	—	31.2	—	0.28
Bureau	88.6	12.8	0.89	0.16
Calhoun	—	25.2	—	0.14
Champaign	18.0	35.2	0.15	0.59
Christian	58.7	66.8	1.03	1.37
Clark	58.0	72.4	0.95	1.03
Coles	—	44.0	—	0.91
Crawford	—	50.8	—	0.75
DeKalb	43.6	5.6	0.86	0.0
Effingham	81.2	85.2	2.29	2.55
Franklin	24.0	17.6	0.28	0.10
Fulton	64.0	40.4	0.77	0.58
Greene	77.6	28.4	0.89	0.22
Iroquois	49.2	20.8	0.47	0.14
Jackson	—	45.6	—	1.11
Jo Daviess	52.8	37.2	0.97	0.55
Kendall	33.2	10.0	0.55	0.07
Knox	15.6	22.8	0.07	0.29
LaSalle	55.2	34.8	0.80	0.46
Lawrence	56.4	52.8	0.83	0.97
Livingston	31.3	17.2	0.76	0.34
Logan	66.8	22.8	2.74	0.30
Macon	—	39.2	—	0.93
Madison	91.6	42.4	2.60	0.82
Marion	41.2	62.6	0.20	0.95
Massac	—	10.4	—	0.08
McDonough	52.4	22.4	0.43	0.32
McHenry	40.8	20.8	0.60	0.30
McLean	66.8	22.8	1.43	0.14
Mercer	21.6	13.2	0.28	0.25
Monroe	64.4	71.6	3.01	1.29
Morgan	66.8	26.8	1.41	0.20
Moultrie	—	46.4	—	0.67
Ogle	58.4	4.4	0.32	0.01
Peoria	—	20.8	—	0.19
Pike	—	10.8	—	0.11
Saline	25.2	29.6	0.37	0.40
Sangamon	34.0	56.8	0.45	1.32
Schuyler	54.4	21.6	0.52	0.36
Shelby	61.2	57.2	0.69	0.54
Vermilion	23.2	1.2	0.12	0.00
Warren	48.0	42.8	0.55	1.68
Washington	86.8	55.2	1.62	0.30
Wayne	—	38.4	—	0.56
White	16.0	48.0	0.05	1.32
Whiteside	10.0	11.2	0.13	0.18
Will	32.4	4.4	0.46	0.03
Winnebago	46.8	23.2	0.79	0.33
Woodford	51.6	29.2	0.75	0.08

2004 ILLINOIS CROP PROTECTION TECHNOLOGY CONFERENCE

WEDNESDAY, JANUARY 7—THURSDAY, JANUARY 8, 2004

ILLINI UNION

UNIVERSITY OF ILLINOIS AT URBANA-CHAMPAIGN

Conference Registration Form

Four ways to register:

1. **Online** registration at <http://www.conferences.uiuc.edu/cptc>
2. **Mail** the registration form and payment to: Cashiering Office, University of Illinois, 162 Administration Building, 506 S. Wright St., Urbana, IL, 61801.
3. **Fax** your registration form to 217-333-9561.
4. **Call** 217-333-2880 or toll-free 877-455-2687 to register by phone. Registration form and check or credit card information must then be received at the above address.

FEIN# 37-6000511 - C-FOAP # 1-301768-912010-305300-912098 - Title: Crop Tech 2004

Registration Fee

On or before December 19th	\$90	\$ _____
After December 19th	\$105	\$ _____

Registration fee includes one copy each of the *2004 Illinois Agricultural Pest Management Handbook (IAPMH)* and the *Proceedings* of the conference.

Name: _____

Organization: _____

Address: _____

City: _____ County: _____

State: _____ Zip: _____

Telephone #: _____ Fax #: _____

E-mail: _____

Check Enclosed (Payable to the University of Illinois)

I prefer to pay by credit card (complete the following information):

American Express Visa Mastercard Discover

Credit Card #: _____ Expiration Date: _____

Signature: _____

NOTE: If paying for more than one person, please **enclose a completed registration form for each person** (one check may be written to cover total payment).

2004 University of Illinois Corn and Soybean Classic Registration Form

Three ways to register:

1. Mail the registration form and method of payment to: Cashiering Office, University of Illinois, 162 Administration Building, 506 S. Wright St., Urbana, IL 61801.
2. Call (217) 333-2880 to register by phone. Registration form and check or credit card information must then be received at the above address.
3. Fax your registration form to Conferences and Institutes at (217) 333-9561.

C-FOAP # 1-903252-912010-305300-199000 FEIN# 37-6000511 Title: Corn Classic 04

I will attend on:

- Jan. 13 (Bloomington) Jan. 14 (Rochelle) Jan. 15 (Moline)
 Jan. 20 (Mt. Vernon) Jan. 21 (Collinsville) Jan. 22 (Springfield)

Name: _____

Organization: _____

Address: _____

City: _____ County: _____

State: _____ Zip Code: _____

Telephone #: _____ Fax #: _____

E-mail: _____

Registration Fee

On or before December 31, 2003	\$35	\$ _____
After December 31, 2003	\$50	\$ _____

Registration fee includes lunch and a proceedings booklet.

Check enclosed (Payable to the University of Illinois)

I prefer to pay by credit card (complete the following information):

American Express Visa MasterCard Discover

Credit card #: _____ Expiration date: _____

Signature: _____

NOTE: If paying for more than one person, please **enclose a completed registration form for each person** (one check may be written to cover total payment).

PLANT DISEASES

Plant Disease Management Information at the ICPTC

A number of sessions at the Illinois Crop Protection Technology Conference (see p. 1) will focus on management of crop diseases.

Wednesday, January 7:

- Symposium A will have a session on resistance issues related to management of soybean and other field crop diseases.
- Seminar 2 will cover corn diseases and their management.
- Seminar 3 will focus on the basics of retail seed treatment.
- Seminar 4 will cover management of forages for better yield and profit, including information on forage diseases that reduce yield, persistence, and quality.

Thursday, January 8:

- Symposium D will cover emerging and challenging pest and production issues.
- Seminar 7 will cover plant and soil diagnosis.
- Symposium F will include a product update in disease management.
- Seminar 11 will cover corn and soybean nematodes.
- Seminar 12 will include information on scouting for diseases and other pests.

Plan to attend as many of these sessions as possible at the Illinois Crop Protection Technology Conference to get new and useful information on field crop diseases and to reduce the “bite” they take out of your yields and profits.—*Dean Malvick*

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